

Form PTO-449 SEP 17 2004 U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1196		SERIAL NO. 09/388,063	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.		FILING DATE Aug. 30, 1999	
				GROUP 2815			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
[Signature]	AA	4,261,698	04/81	Carr et al.			
	AB	4,691,662	09/87	Roppel et al.			
	AC	5,261,961	11/93	Takasu et al.			
	AD	5,270,241	12/93	Dennison et al.			
	AE	5,312,783	05/94	Takasaki et al.			
	AF	5,392,189	02/95	Fazan et al.			
	AG	5,395,771	03/95	Nakato			
	AH	5,468,687	11/95	Carl et al.			
	AI	5,525,156	06/96	Manada et al.			
	AJ	5,614,018	03/97	Azuma et al.			
[Signature]	AK	5,656,329	08/97	Hampden-Smith			
	AL	5,663,089	09/97	Tomozawa et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
[Signature]	AM	EP 0 030 798	06/81	EPO - Hughes			N/A
	AN	GB 2 194 555 A	03/88	UK - Nippon			N/A
	AO	EP 0 306 069 A2	03/89	EPO - Phillips			N/A
	AP	EP 0 388 957 A2	09/90	EP - NEC Corp			N/A
	AQ	JP 2250970	10/90	Japan - NEC Corp			ABS
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
[Signature]	AR	Aoyama et al., "Leakage Current Mechanism of Amorphous and Polycrystalline Ta ₂ O ₅ Films Grown by chemical Vapor Deposition," 1995, pages 977-983.					
	AS	Stemmer et al., "Accommodation of nonstoichiometry in (100) fiber-textured ... thin films grown by chemical vapor deposition," ©1999 American Institute of Physics, pages 2432-2434.					
[Signature]	AT	Streiffner et al., "Ferroelectricity in thin films: The dielectric response of fiber-textured ... thin films grown by chemical vapor deposition," ©1999 American Institute of Physics, pages 45654575.					
EXAMINERS				DATE CONSIDERED 12/10/94			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PT 159 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1196		SERIAL NO. 09/388,063				
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Vishnu K. Agarwal et al.						
		FILING DATE Aug. 30, 1999		GROUP 2815				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
[Signature]	AA	5,702,562	12/97	Wakahara				
	AB	5,719,417	02/98	Roeder et al.				
	AC	5,723,361	03/98	Azuma et al.				
	AD	5,736,759	04/98	Hausaalter				
	AE	5,976,990	11/99	Mercaldi et al.				
	AF	5,989,927	11/99	Yamonobe				
	AG	6,101,085	08/00	Kawahara et al.				
	AH	6,215,650	04/01	Gnade et al.				
	AI	6,258,654	07/01	Gocho				
	AJ	6,287,935	09/01	Coursey				
	AK	6,325,017 B1	12/01	DeBoer et al.				
	AL	6,335,049 B1	01/02	Basceri				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
[Signature]	AM	JP 04-24922	01/92	Japan - Mitsubishi			X	
	AN	JP 04-115533	04/92	Japan - Oki Elec.			X	
	AO	JP 04-180566	06/92	Japan - Mitsuhsita			ABS	
	AP	JP 08-060347	03/96	Japan - Fujitsu			X	
	AQ	EP 0 810 666 A1	12/97	EPO - Oki Electric			N/A	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR		[Diagonal line through the table]					
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
[Signature]				12/10/94				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1196		SERIAL NO. 09/388,063	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.		FILING DATE Aug. 30, 1999	
				GROUP 2815			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,566,147 B2	05/03	Basceri et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM	EP 0 892 426 A2	01/99	EPO - Ramtron			Yes No
	AN	JP 2000091333	03/00	Japan			X
	AO	WO 01/16395	03/01	WIPO - Micron			N/A
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER 				DATE CONSIDERED 12/10/4			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							